

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Bruno GHYSELEN et al.

Application No:

Group Art Unit:

Filing Date:

Examiner:

For: METHOD AND APPARATUS FOR
ADJUSTING THE THICKNESS OF A
LAYER OF SEMICONDUCTOR MATERIAL

Atty. Docket No.: 4717-6400

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed is a PTO form 1449 which lists (8) cited references for the Examiner's review and consideration. These references were cited on the Search Report for the corresponding French application, a copy of which is enclosed.

Pursuant to the recent rule change, only copies of the foreign references are enclosed. Copies of the U.S. references are not submitted. (see Official Gazette notice at <http://www.uspto.gov/web/offices/com/sol/og/2003/week31/patdisc.htm>), It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee or certification is believed to be due for this submission since the references are being submitted concurrent with the filing of this application. Should any fees be required, however, please charge such fees to **Winston & Strawn** Deposit Account No. 501-814.

Date: 8/6/03

Respectfully submitted,


Allan A. Fanucci (Reg. No. 30,256)

WINSTON & STRAWN
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Enclosures

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NY:799569.1

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| | | | | 87534-6400 | | | | |
| | | | | APPLICANT: | | | | |
| | | | | Bruno GHYSELEN et al. | | | | |
| | | | | FILING DATE: | | GROUP: | | |
| U.S. PATENT DOCUMENTS | | | | | | | | |
| *EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE | |
| | AA | 6,096,233 | 8/2000 | Taniyama et al. | 216 | 92 | | |
| | AB | 6,111,634 | 8/2000 | Pecen et al. | 356 | 72 | | |
| | AC | 6,406,924 | 6/2002 | Grimbergen et al. | 438 | 9 | | |
| | AD | 2002103564 | 8/2002 | Fielden et al. | 700 | 121 | | |
| | | 2002102749 | 8/2002 | Fielden et al. | 438 | 014 | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | | |
| | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
| | | | | | | | YES | NO |
| | AE | EP 0881 040 | 12/1998 | Europe | | | X | |
| | AF | FR 2 797 714 | 2/2001 | France | | | X | |
| | AG | WO 02 257 08 | 3/2002 | PCT | | | X | |
| | AH | | | | | | | |
| | AI | | | | | | | |
| OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | | |
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| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609 ; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | | | |